



501.38036X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): SHISHIDO, et al
Serial No.: 09/473,296
Filed: December 28, 1999
For: METHOD AND EQUIPMENT FOR DETECTING PATTERN DEFECT
Group: 2878
Examiner: C. Hannaher

AMENDMENT

Mail Stop Fee-Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 10, 2003

Sir:

In response to the Office Action dated April 10, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application, as listed below and as set forth on the following pages:

Amendments to the Specification;

Amendments to the Claims; and

Remarks are included following the amendments; and

An Appendix including corrected drawings is attached following the remarks.

BEST AVAILABLE COPY

10/16/2003 WASFAW1 00000067 09473296

02 FC:1201

86.00 OP

TECHNOLOGY CENTER 2800

OCT 20 2003

RECEIVED